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NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10057674	01/24/2002	430		1756	BARRECA, N

APPLICANTS: Hwang Jeng; Mak Steve; Lin Tru-Lon; Ying Chentsau; Schaller John;

CONTINUING DATA VERIFIED:

This application is a CON of 09/421,467 10/19/1999 ABN
which is a CIP of 09/251,588 02/17/1999 ABN
and is a CIP of 09/251,826 02/17/1999 PAT 6,323,132
and is a CIP of 09/251,633 02/17/1999 PAT 6,265,318
which is a CIP of 09/006,032 01/13/1998 ABN

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FOREIGN APPLICATIONS VERIFIED: none

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	ATTORNEY DOCKET NO
Foreign priority claimed	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no		AM-2602.C1
35 USC 119 conditions met	<input type="checkbox"/> yes <input checked="" type="checkbox"/> no		
Verified and Acknowledged Examiners's initials			
TITLE: Masking methods and etching sequences for patterning electrodes of high density RAM capacitors			

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
		Total Claims	Print Claim for O.G
Assistant Examiner		DRAWING	
ISSUE FEE		Sheets Drwg.	Figs. Drwg.
Amount Due	Date Paid	Print Fig.	
Primary Examiner		Application Examiner	
PREPARED FOR ISSUE			
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